Nanoscale characterization of individual horizontally aligned single-walled carbon nanotubes

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Received XXXX, revised XXXX, accepted XXXX
Published online XXXX

Key words: SNOM, nanotube, carbon, individual, aligned, horizontally, nanoscale, nano

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One of the most challenging tasks in nanotube research is to identify the different electronic type of nanotubes for device fabrication. The implementation of standard spectroscopy techniques at the single-tube level has remained a great task due to small nanotube signal and low spatial resolution. Scattering-type scanning near-field optical microscopy (s-SNOM) yields information on the optical characteristics of the sample with high spatial resolution.

We have already demonstrated that this method is able to distinguish between different electronic types of carbon nanotube bundles based on their optical properties in the infrared region. Now we applied the same method to characterize individual horizontally aligned single-walled carbon nanotubes (SWCNT).

1 Introduction Single-walled carbon nanotubes are still in the focus of research due to their unique physical properties. They are identified by their chirality which dictates the physical structure and electronic properties of the individual species. The selective production of carbon nanotubes is still under intense research for device fabrication like FET arrays [1], high performance electronics [2] and low noise amplifiers [3]. The characterization of the individual products of selective growth is an important and difficult task. Because of the size of individual nanotubes, it is still a challenge. The diffraction-limited spatial resolution of standard optical methods being insufficient for the study of objects of such size, alternative methods have to be used. Scattering-type scanning near-field optical microscopy combines high spatial resolution with low detection threshold of optical properties of materials even on the nanoscale.

2 Experimental methods The scattering-type near-field optical microscope setup provides completely wavelength-independent resolution. It is basically the combination of an atomic force microscope (AFM) and a Michelson interferometer (Fig. 1). The AFM part employs standard Si probing tips with metal coating. The end of the tip is illuminated with a focused laser beam. The light from this laser induces a strong evanescent electromagnetic field which can interact with the sample. The interaction between the near-field and the sample influences the backscattered light in a way that can be described by a complex scattering coefficient \( \sigma = se^{i\phi} \). The light scattered back along the illumination path is collected and recorded as the optical signal.

Because only a small part of the scattered light is coming from the tip, the AFM is working in tapping mode to modulate the near-field interaction and the scattered light is analyzed by pseudo-heterodyne detection with the interferometer. Demodulating the acquired signal at higher harmonics \( (n\text{th}) \) of the tip oscillation frequency \( (\Omega) \), we can obtain the amplitude \( (s_n) \) and the phase \( (\phi_n) \) of the scattered light [4]. The higher order we demodulate the sig-
nal the more it will contain from the near-field scattering. In our experiments we used the second (O2) and the third (O3) harmonic demodulation.

Our s-SNOM instrument was produced by Neaspec GmbH. As probing tip we used commercially available Pt-coated Si AFM tips purchased from NanoWorld. The illuminating unit was a tunable quantum cascade laser (QCL) with frequency range \( 960 - 1020 \text{ cm}^{-1} \).

3 Sample preparation The horizontally aligned SWCNTs were individually grown by CVD technique. After the growing phase the nanotubes were transferred between gold contacts generated by lithography on a Si/SiO\(_2\) substrate [5]. Metallic nanotubes were subsequently destroyed by the electrical breakdown technique [5–7]. Scanning electron microscopy (SEM) images of the samples before and after breaking the metallic nanotubes are shown in Fig. 2.

In our previous study we predicted the difference in the near-field scattered signal in case of metallic or semiconducting nanotube bundles by using the Extended Finite Dipole Model (EFDM) [9]. This model approximates the tip-nanosphere-substrate system with several dipoles. We exchanged the nanosphere to a cylinder by replacing its polarizability to that of a prolate ellipsoid with high aspect ratio [10].

The outcome of this calculation [11] is shown in Fig. 4. The results verify our expectations. The calculation yields that the metallic nanotubes have higher near-field phase signal relative to the substrate. The near-field phase contrast of the semiconducting nanotubes remains near zero in the range of interest.

5 Results and discussion We performed the s-SNOM experiment on the sample mentioned above. The nanotubes are located between the gold contacts, on a SiO\(_2\) substrate. The optical properties of the substrate are crucial for the measurement, as the substrate has to provide appreciable near-field signal in order to have the appropriate coupling between the nanoparticle and the tip. Fortunately
SiO$_2$ has almost as high near-field scattering as Si in this infrared region.

The AFM topography map of the sample can be seen in Fig.5. For high resolution s-SNOM measurements we chose a clean area (indicated by the green rectangle) where the nanotubes are properly separated to measure them individually. The chosen area contains two metallic nanotube candidates.

The outcome of the high resolution third-harmonic demodulated measurements at 985 cm$^{-1}$ is presented in Fig.6. The upper map is the corresponding AFM topography. The blue boxes indicate the metallic nanotube candidates. The diameter of these metallic tubes are approximately 3 nm and 1.7 nm. The third-harmonic demodulated phase map ($\varphi_{O3}$) was acquired simultaneously and is presented in the lower part of Fig.6. The phase responses of the individual nanotubes are similar to those of the bundles. We find that the two metallic candidates give the highest phase response, with the larger tube showing $\varphi_{O3} \approx 0.168$ [rad] and the smaller $\varphi_{O3} \approx 0.132$ [rad]. It is very important to note that in general the size of the nanoparticle influences the near-field contrast between the substrate and the particle [12].

The O3 phase map also shows that the largest semiconducting tube (2.5 nm) exhibits a lower phase signal than the smallest metallic one. Based on these observations we can declare that all nanotubes in this area with lower phase contrast than the 1.7 nm metallic carbon nanotube, are semiconducting ones.

We also examined the spectral behavior of these individual nanotubes. Fig. 7 shows the result of these measurements. We can conclude from the spectra that the frequency dependence of the near-field phase signal follows that of the imaginary part of the dielectric function.

We find that at higher wavenumbers (1025 cm$^{-1}$) the phase of the semiconducting nanotubes is obstructed by the noise, but the phase of the metallic ones is still detectable.

6 Conclusions In our study we found that near-field infrared imaging of individual SWCNTs is possible even on a SiO$_2$ substrate. We proved that the electrical breakdown technique destroys partially only the metallic nanotubes. The spectroscopic study verifies that the near-field phase is connected with the imaginary part of the dielectric function.

Acknowledgements Research supported by the Hungarian National Research Fund (OTKA) No. SNN 118012.

References

Figure 6 AFM topography image of the chosen area for high resolution s-SNOM measurements (above) and the O3 near-field phase map at 985 cm$^{-1}$ of the same area (below). The blue boxes indicate the metallic nanotube candidates. The red box stands for the largest semiconducting nanotube.

Figure 7 Third-harmonic demodulated (O3) near-field phase spectra of a semiconducting (red) and metallic (blue) carbon nanotube.